

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST
CERTIFICATES FOR ELECTRICAL EQUIPMENT
(IECEE) CB SCHEME

SYSTEME CEI D'ACCEPTATION MUTUELLE DE
CERTIFICATS D'ESSAIS DES EQUIPEMENTS
ELECTRIQUES (IECEE) METHODE OC

CB TEST CERTIFICATE**CERTIFICAT D'ESSAI OC**

Product
Produit

Notebook PC

Name and address of the applicant
Nom et adresse du demandeur

ASUSTEK COMPUTER INC
4TH FL 150 LI-TE RD
PEITOU
TAIPEI, 112 Taiwan

Name and address of the manufacturer
Nom et adresse du fabricant

ASUSTEK COMPUTER INC
4TH FL 150 LI-TE RD
PEITOU
TAIPEI, 112 Taiwan

Name and address of the factory
Nom et adresse de l'usine

PROTEK (SHANGHAI) LTD
3768 XIU YAN RD KANGQIAO TOWN PUDONG NEW
DISTRICT 201319 SHANGHAI
CHINA

Note: When more than one factory, please report on page 2
Note: Lorsque il y a plus d'une usine, veuillez utiliser la 2^{ème} page

Additional Information on page 2
19Vdc, 2.37A or 19Vdc, 3.42A (optional)

Ratings and principal characteristics
Valeurs nominales et caractéristiques principales

Trademark (if any)
Marque de fabrique (si elle existe)

ASUSTek Computer Inc



Type of Manufacturer's Testing Laboratories used
Type de programme du laboratoire d'essais
constructeur

Model / Type Ref.
Ref. De type

BX32xyyyyyyyyyy, UX32xyyyyyyyyyy
See Page 2

Additional information (if necessary may also be
reported on page 2)
Les informations complémentaires (si nécessaire,,
peuvent être indiqués sur la 2^{ème} page

Additional Information on page 2

A sample of the product was tested and found
to be in conformity with
Un échantillon de ce produit a été essayé et a été
considéré conforme à la

IEC 60950-1(ed.2), IEC 60950-1(ed.2);am1

As shown in the Test Report Ref. No. which forms
part of this Certificate
Comme indiqué dans le Rapport d'essais numéro de
référence qui constitue partie de ce Certificat

ASL13010237-001 issued on 2013-12-25

This CB Test Certificate is issued by the National Certification Body
Ce Certificat d'essai OC est établi par l'Organisme **National de Certification**



- UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA
- UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK
- UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN
- UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

For full legal entity names see www.ul.com/ncbnames

Date: 2013-12-26
Original Issue Date: 2013-01-11

Signature:

Jan-Erik Storgaard



Ref. Certif. No.

DK-30331-A1-UL

Model Details:

BX32xyyyyyyyy,UX32xyyyyyyyy (x = 0-9, A-Z, a-z, - or blank; y = 0-9, A-Z, a-z, - or blank for marketing purpose and no impact safety related construction and critical components)

Factories:

PEGATRON CORP TAOYUAN MFG
5, SHING YEH ST., KWEI SHAN HSIANG, TAOYUAN 333,
TAIWAN

TECH-COM(SHANGHAI) COMPUTER CO. LTD
68 SANZHUANG RD, SONGJIANG EXPORT PROCESSING ZONE, SHANGHAI 201613,
CHINA

DIGITEK (CHONGQING) LIMITED
B01,SECTION C,AIRPORT FUNCTION ZONE,LIANGLU CUNTAN FREE TRADE PORT AREA,YUBEI DISTRICT
CHONGQING CITY,
CHINA

COMPAL INFORMATION (KUNSHAN) CO.LTD
NO.15, THIRD AVENUE, A ZONE, KUNSHAN COMPREHENSIVE FREE TRADE ZONE, KUNSHAN, JIANGSU,
CHINA

COMPAL INFORMATION TECHNOLOGY (KUNSHAN) CO.LTD
NO.58, FIRST AVENUE, A ZONE, KUNSHAN COMPREHENSIVE FREE TRADE ZONE, KUNSHAN, JIANGSU,
CHINA

COTEK ELECTRONICS (SUZHOU) CO LTD
288 MAYUN RD NEW DISTRICT SUZHOU JIANGSU 215011
CHINA

Additional Information:

Additionally evaluated to EN 60950-1:2006/A11:2009/A1:2010/A12:2011.

National Difference specified in the CB Test Report.

The original report was modified to include the following changes/additions:

1. Change model name.
2. Add alterne components.
3. Add Australia/New Zealand National differences.

Additional information (if necessary)

Information complémentaire (si nécessaire)



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